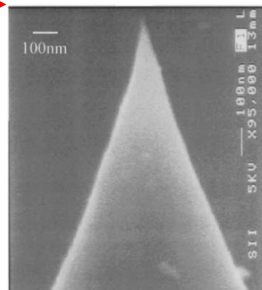


Replaceable AFM tip



AFM scanning tip

About

NF-01 is an ultra-high resolution sensing probe capable of resolving nanoNewton force and sub-nanometer displacement. The small package houses both the readout electronics and replaceable sensing head, can be easily mounted on various surfaces and setups. It is usable in air, vacuum, and liquid environment.

Features

- Highest force and displacement sensing resolution.
- Low signal drift, highly repeatable measurement.
- Varies tip shape available for indentation, compression and tensile testing.
- Plug-and-play USB connection with intuitive software interface.
- High quality, low cost replaceable sensing tips.

Applications

- Materials characterizations
- MEMS device testing
- Actuator calibration
- Transducer calibration
- Quality control
- Atomic force microscopy
- Cell mechanics
- Micro-nano manipulation
- Dimensional Metrology

Specifications

Force Sensing	Resolution	5 nN at 1 kHz
	Range	+/- 400 μ N
	Accuracy	20 nN
	Drift	<20 nN/minute
Displacement Sensing	Resolution	0.1 nm at 1 kHz
	Range	+/- 7 μ m
	Accuracy	0.5 nm
	Drift	<0.5 nm/minute
Interface	Mechanical mounting	Screw, spring clip, adhesive
	Electrical	USB communication

For additional information, please visit www.to-nano.com, or contact info@to-nano.com